Docket No.: 67161-127 **PATENT**

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Customer Number: 20277

Yoshiharu ONO

Confirmation Number:

Serial No.:

Group Art Unit:

Filed: November 6, 2003

Examiner:

For:

METHOD OF MANUFACTURING SEMICONDUCTOR DEVICE

INFORMATION DISCLOSURE STATEMENT

Mail Stop IDS Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the document listed on the attached form PTO-1449. It is respectfully requested that the document be expressly considered during the prosecution of this application, and that the document be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

The relevance of Japanese Patent Laying-Open No. 2001-358216, is discussed in the present specification.

Serial No.:

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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Date: November 6, 2003

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION					ATTY. DOCKET NO. SE 67161-127		ERIAL NO.		
					APPLICANT Yoshiharu ONO				
(PTO-1449)					FILING DATE GROUI		OUP	JP	
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U.S. PATENT					NT DOCUMENTS				
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1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.